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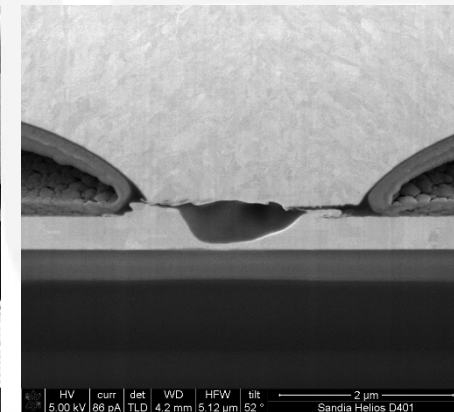
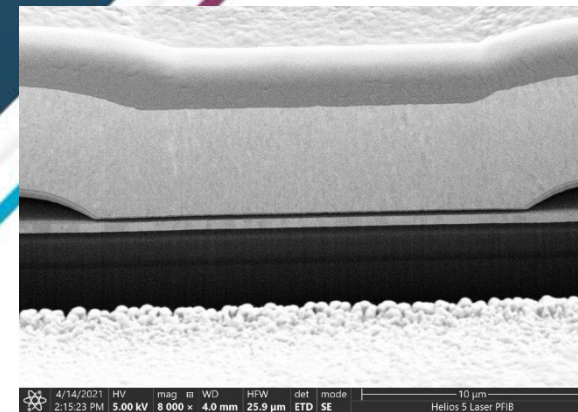
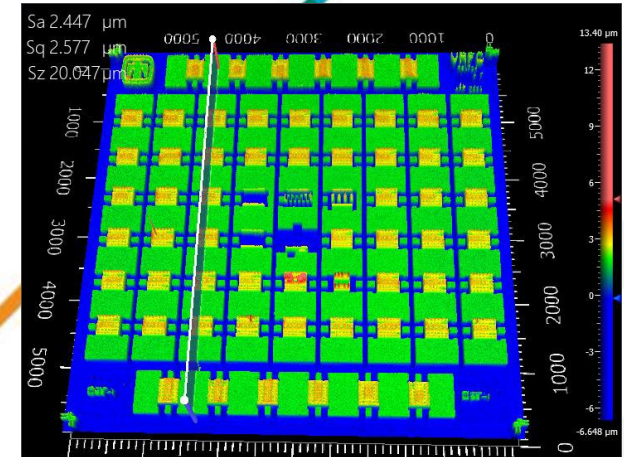
Devices and Experiments for Exploring RF Breakdown in Micrometer-Scale Air Gaps

July 13, 2022

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2022 AP-S/URSI Meeting, Denver, CO USA



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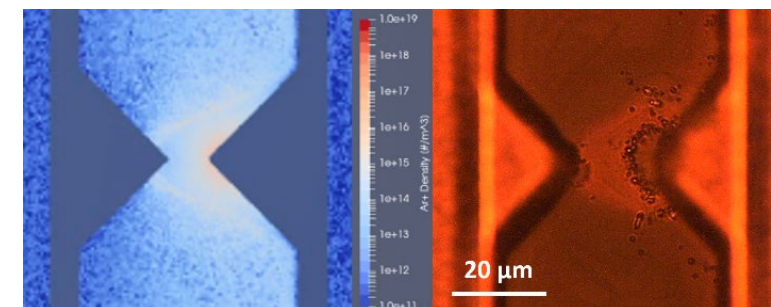
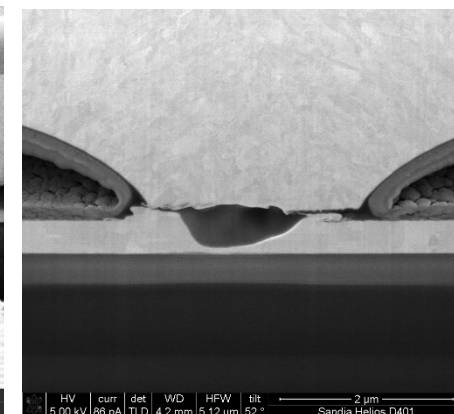
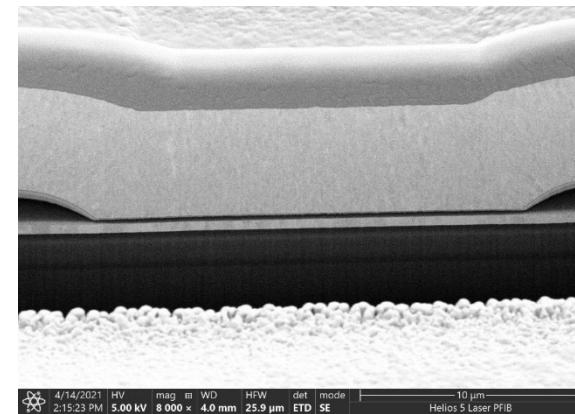
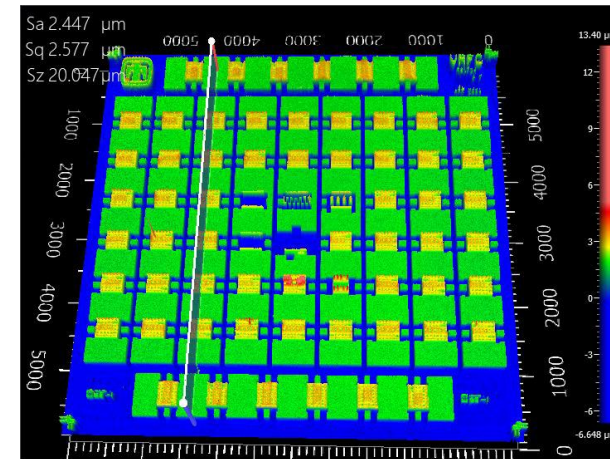
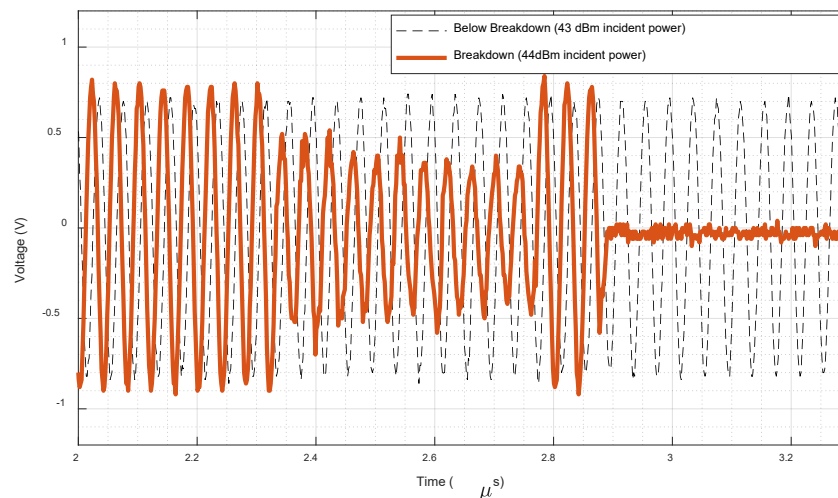
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Outline

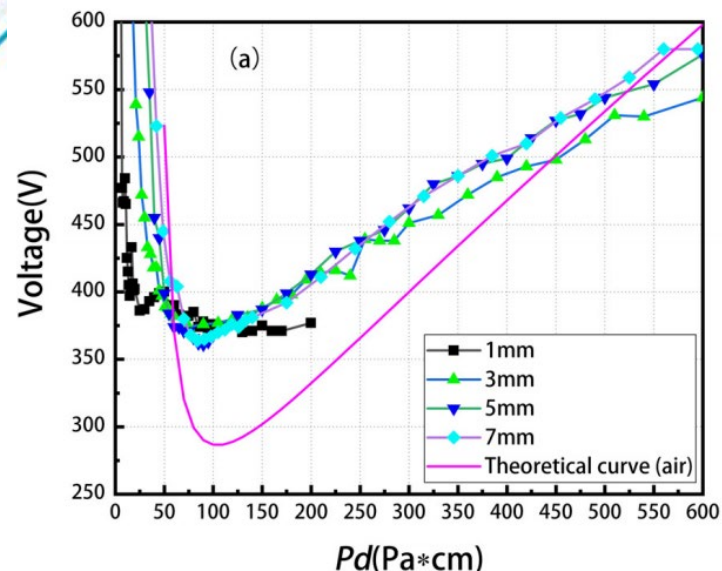
- Introduction – Breakdown in Narrow Gaps & at RF
- Motivation – Fix It Or Feature It
- Device Design and Challenges
- Fabrication – Double Release Process
- DC Test and Screening Results
- RF Power and Time-Domain Results
- Next Steps
- Conclusions





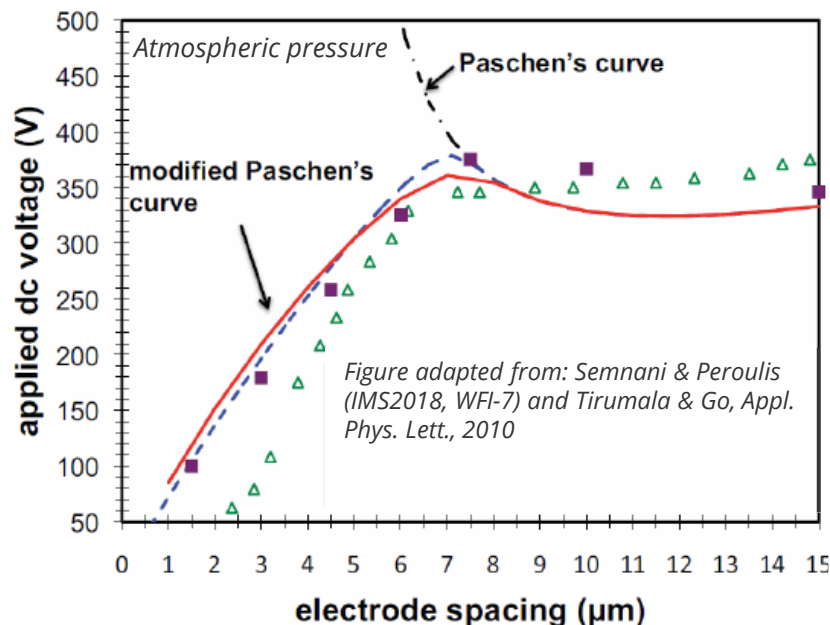
Introduction – Breakdown in Narrow Gaps & at RF

Paschen's Curve

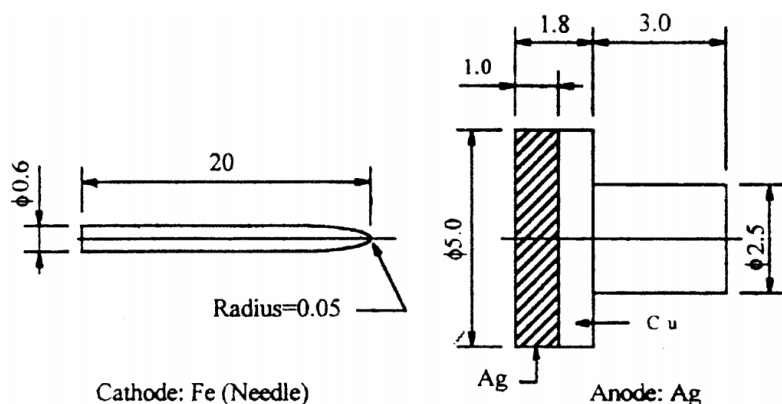
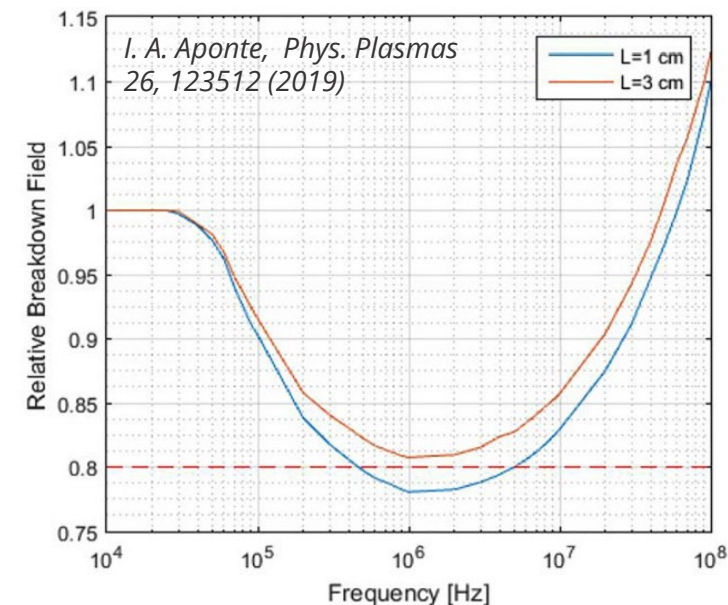


X. Lyu, et al., *Phys. Plasmas* 27, 123509 (2020)

DC Narrow Gaps



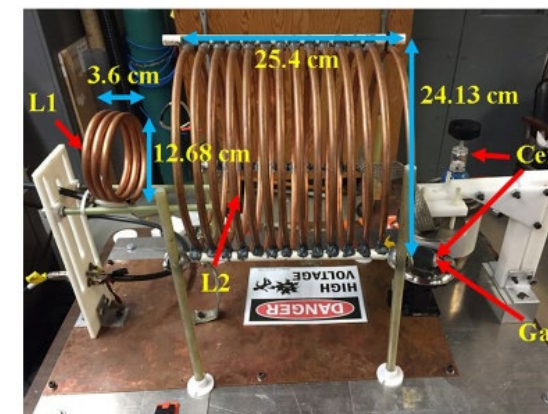
Radiofrequency



Slade and Taylor, *IEEE Trans. Comp. Pack. Tech.*, 25, 2002.



I. A. Aponte, *Phys. Plasmas* 26, 123512 (2019)

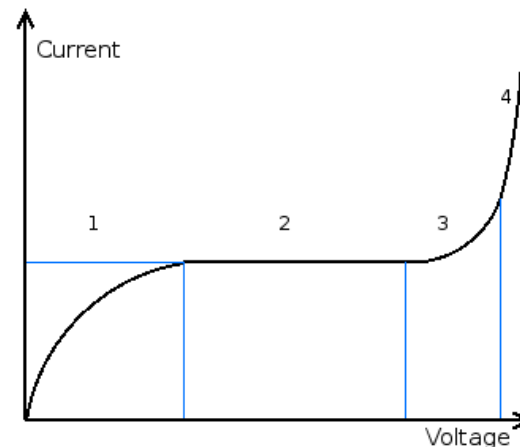
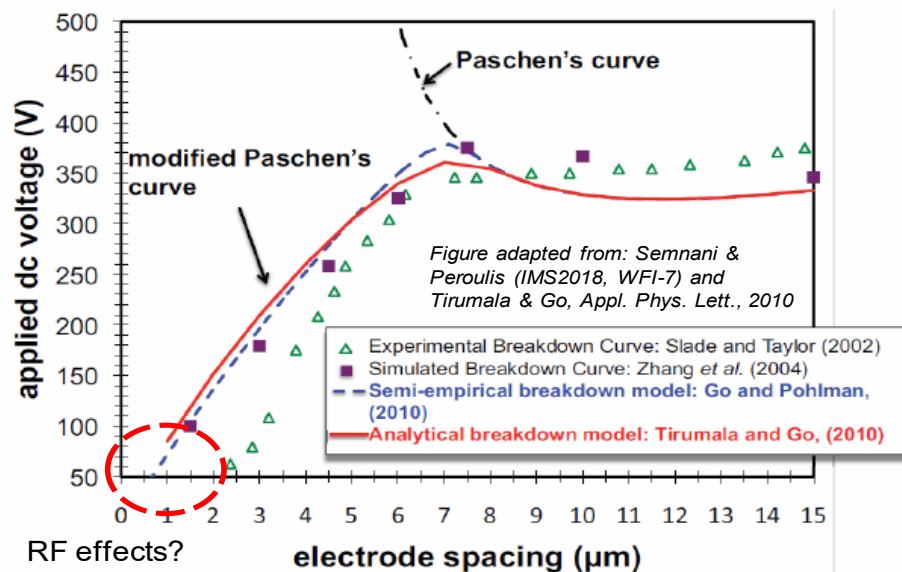


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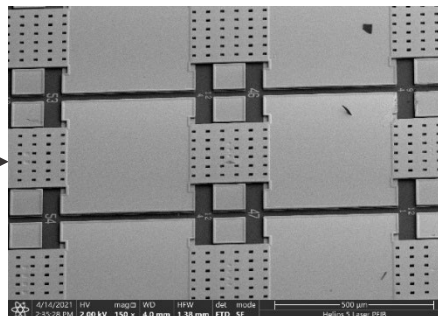
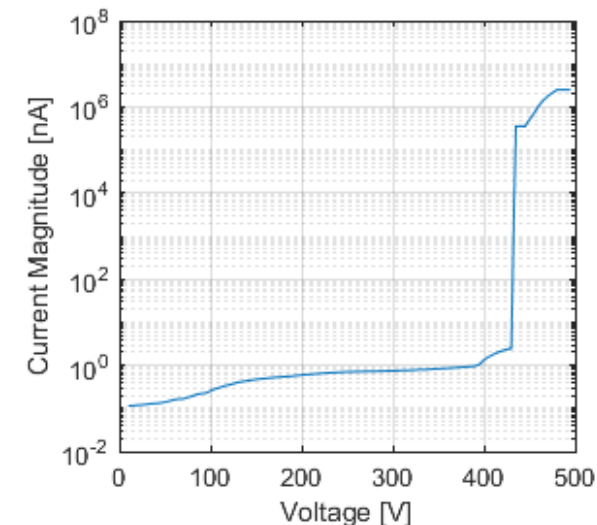


Motivation – “Fix It Or Feature It”

- Encourage Breakdown Where Desired, Mitigate Breakdown When It Isn't
- Narrow gaps and RF frequencies may reduce voltage relative to DC case
 - Synergistic effects could cause lower breakdown

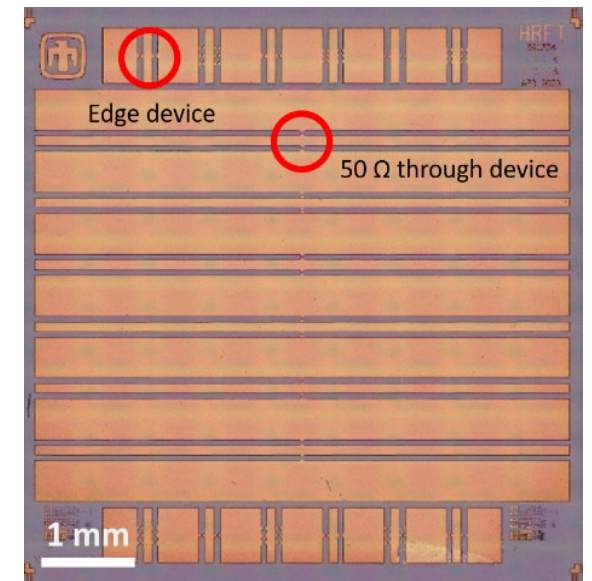
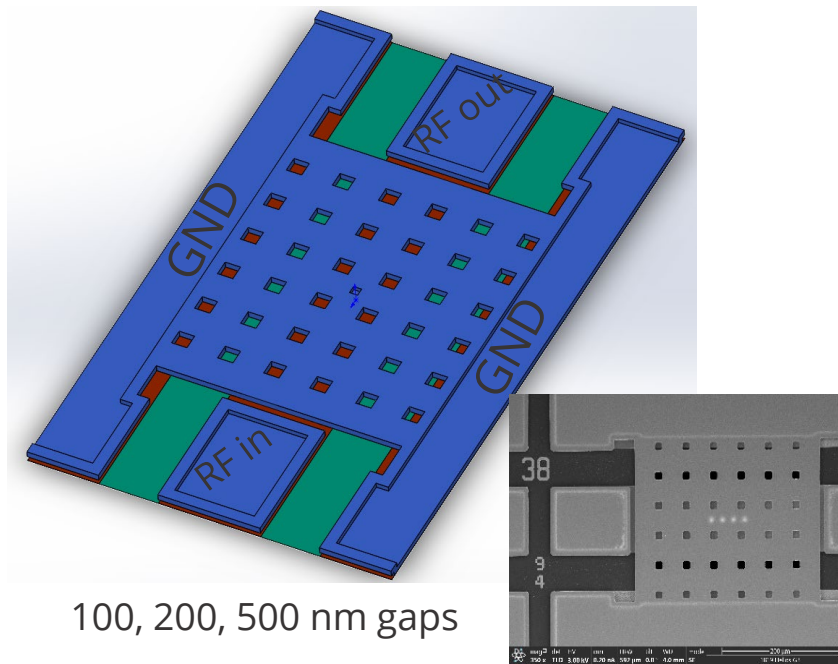
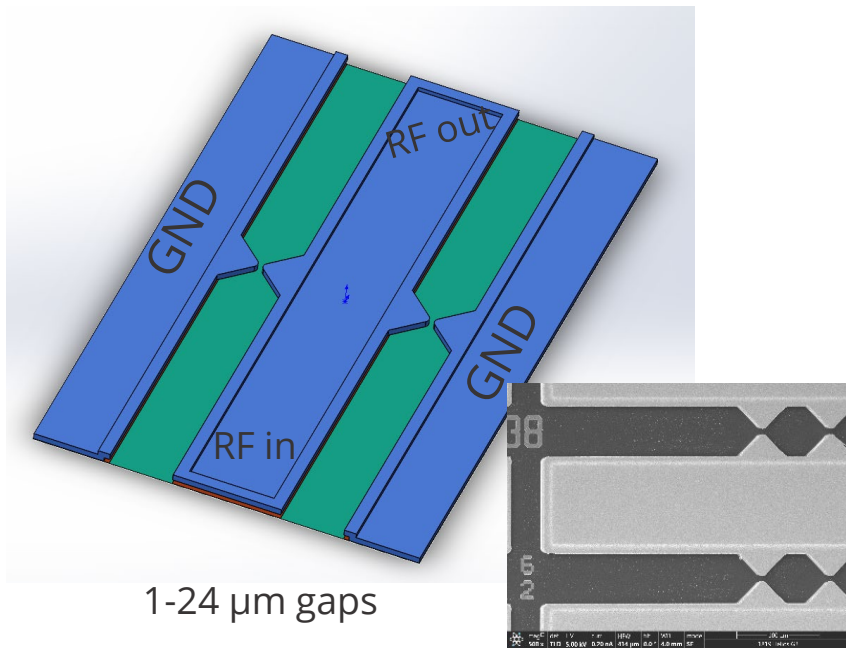


Measurement



Device Design and Challenges

- Challenge: Integrated RF/Narrow gap devices with gaps $0.1 - >20\ \mu\text{m}$
 - GSG, $50\ \Omega$ coplanar waveguide lines, modeled/designed to account for additional capacitance of gaps
 - Horizontal (in-plane) and vertical (out-of-plane) gaps

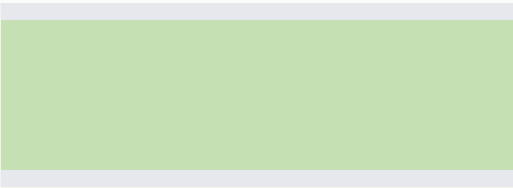


- Other benefits:
 - Microfabricated dimensions for field enhancement investigations
 - Lithographic and fabrication enabled fine control over design-of-experiments

Fabrication – Double Sacrificial Layer

- Vertical and horizontal style devices are co-fabricated using a double release/sacrificial layer process

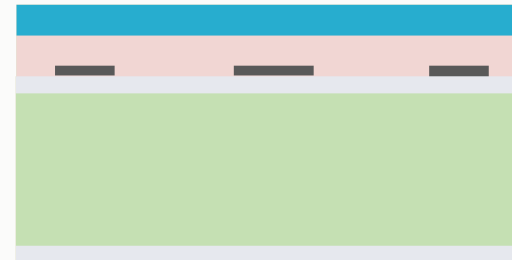
1. Oxide Deposition (Diffusion)



2. Litho/Au Dep/Liftoff



3. Germanium Dep & PMGI Spin



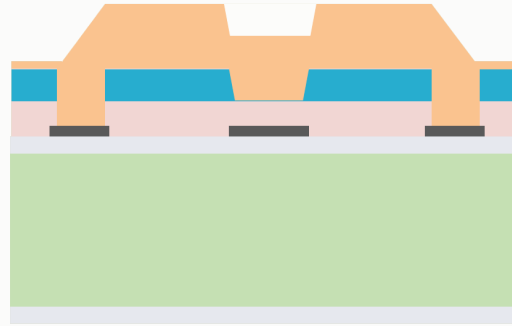
4. Dimple Litho/Etch



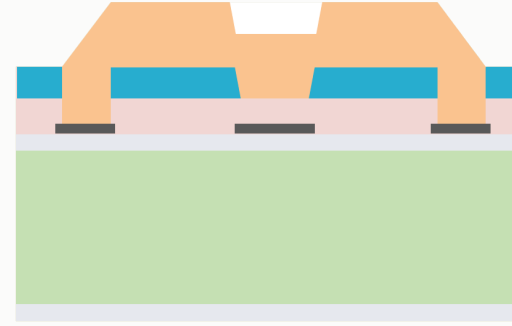
5. Air Bridge Litho/Etch



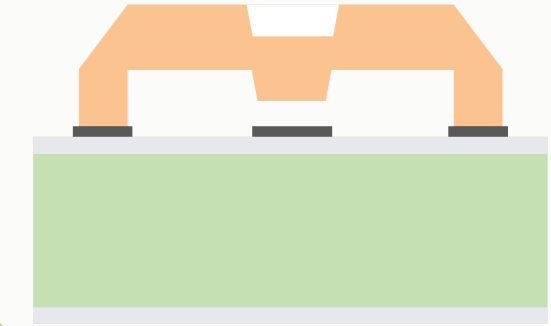
6. Au Seed/Plating



7. Seed Layer Etch (IBE)

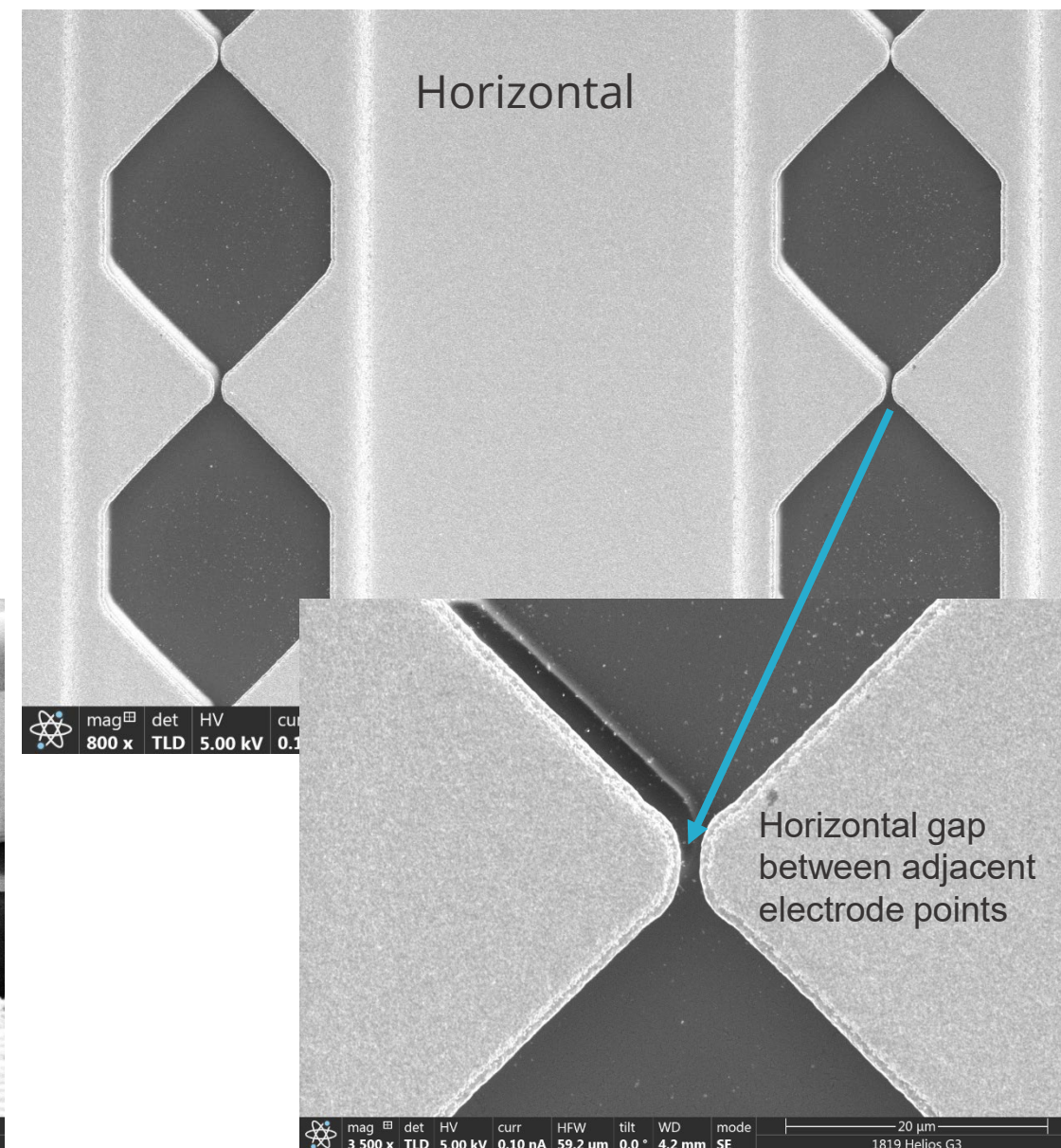
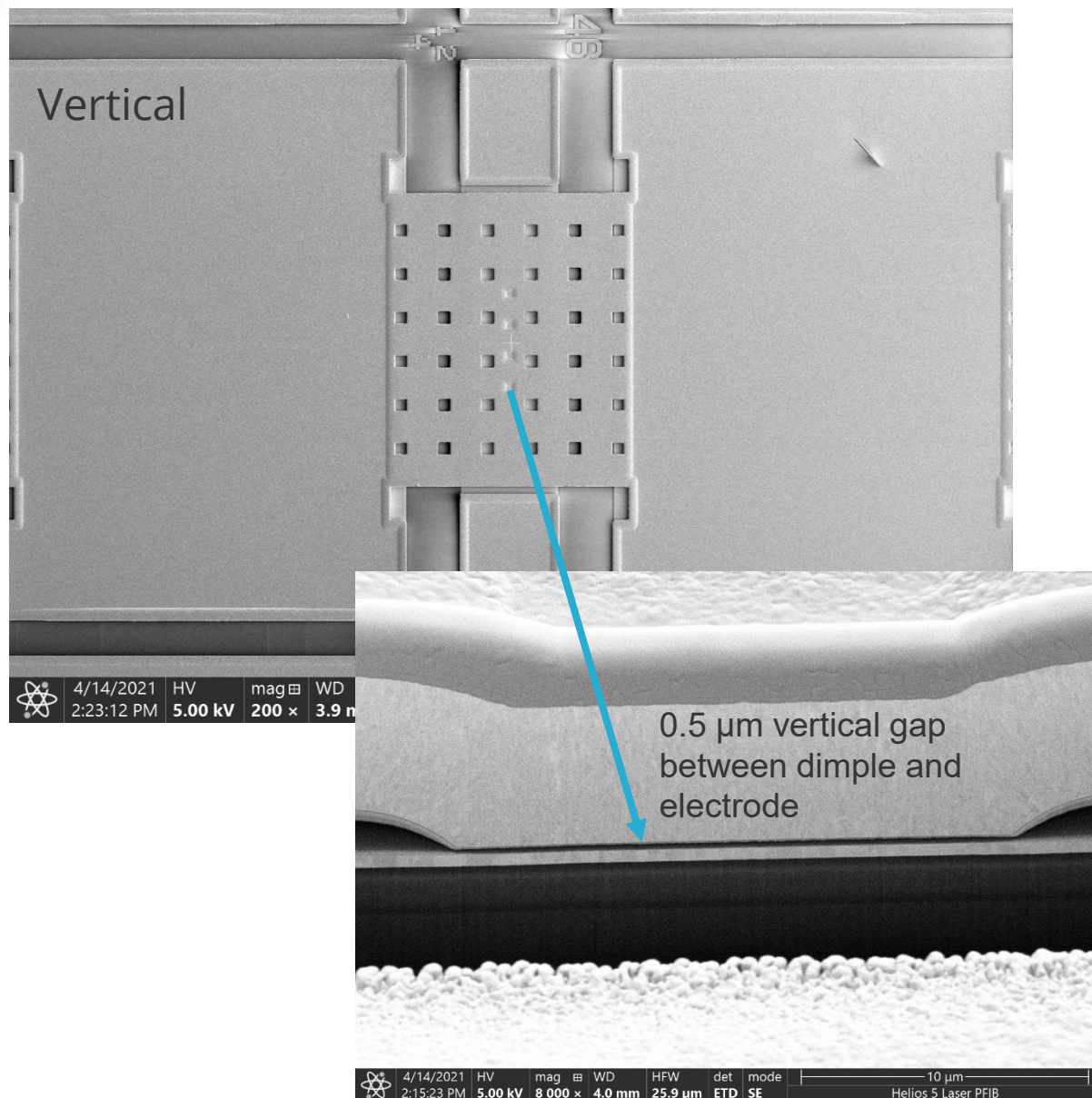


8. Wet & Dry Release





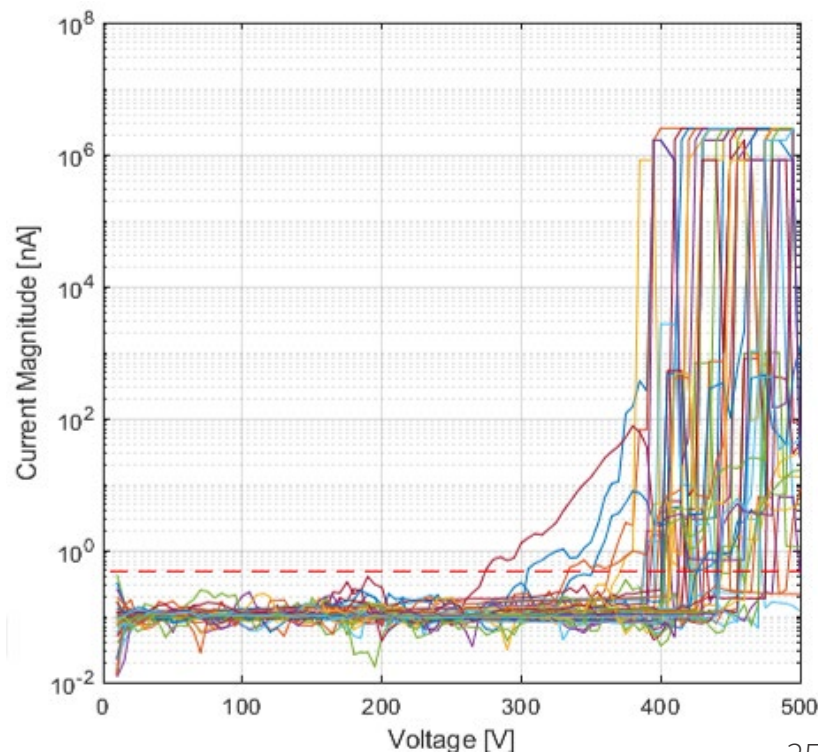
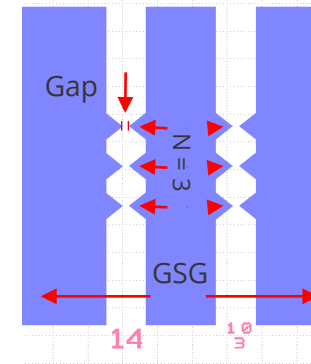
Fabrication – Results



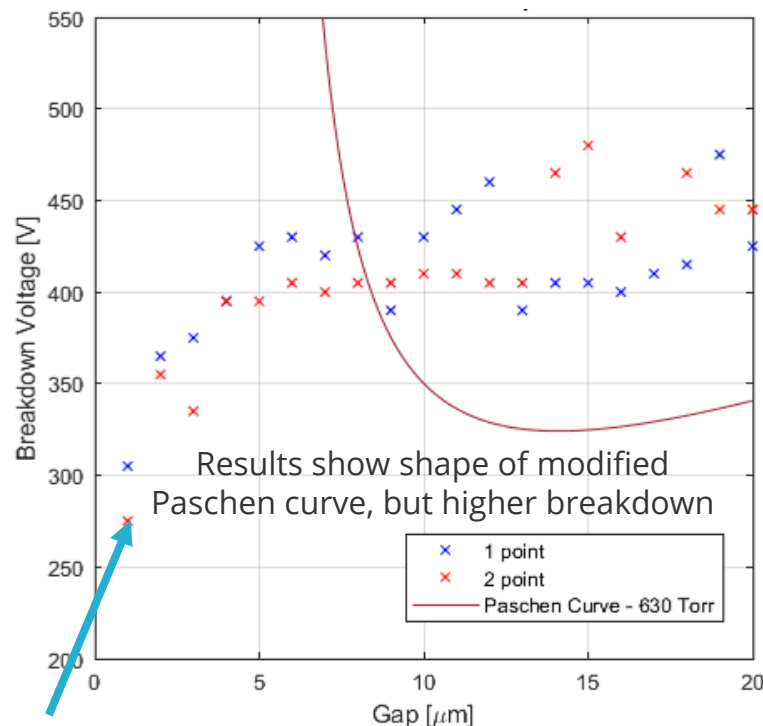


DC Screening Results – Horizontal Devices

- Example data from **horizontal** device die
 - measured using Keithley 6487 Picoammeter & custom python script

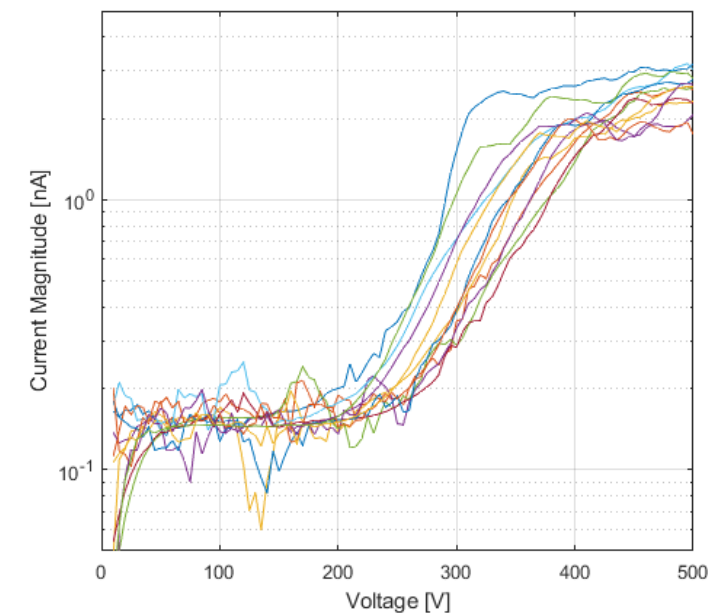


IV curves each correspond to a separate device



250 V_{peak} is ~625 Watts in 50 Ω

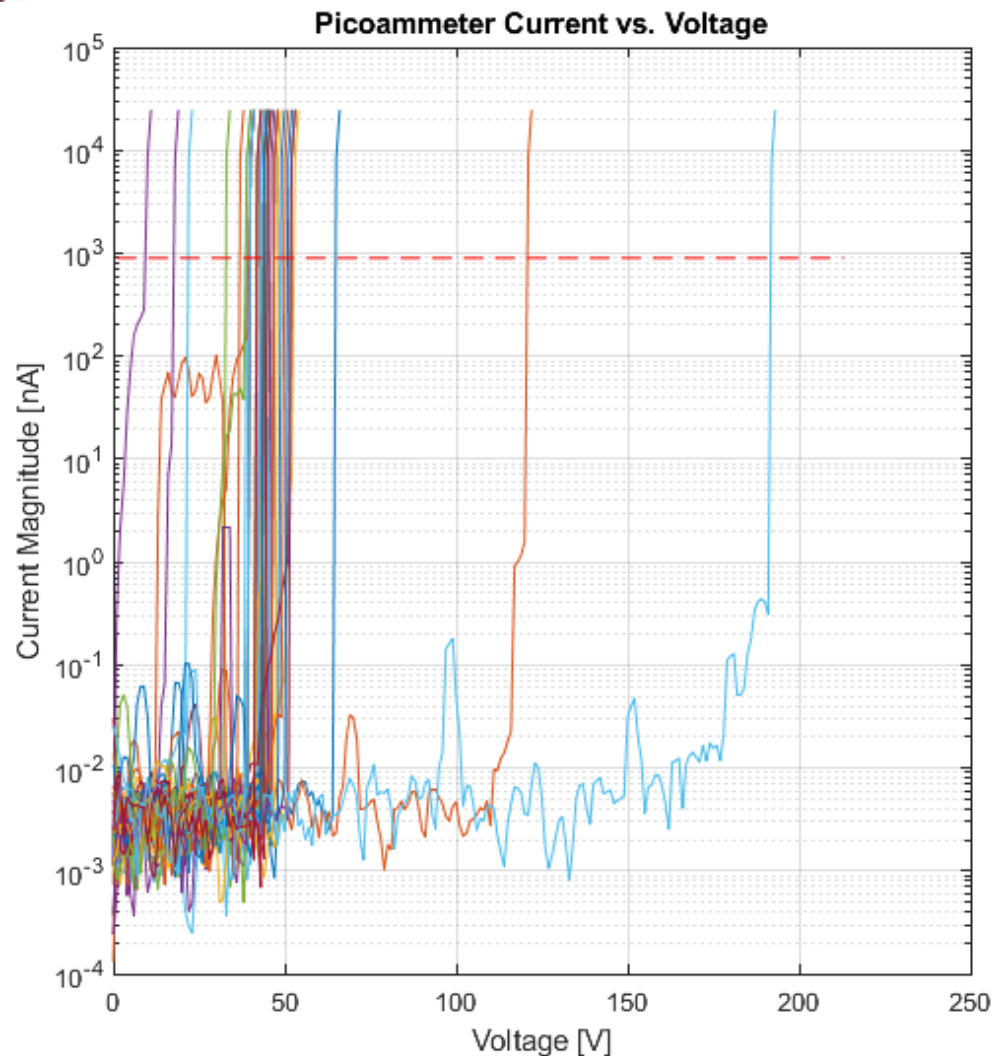
Onset of breakdown vs. plasma gap



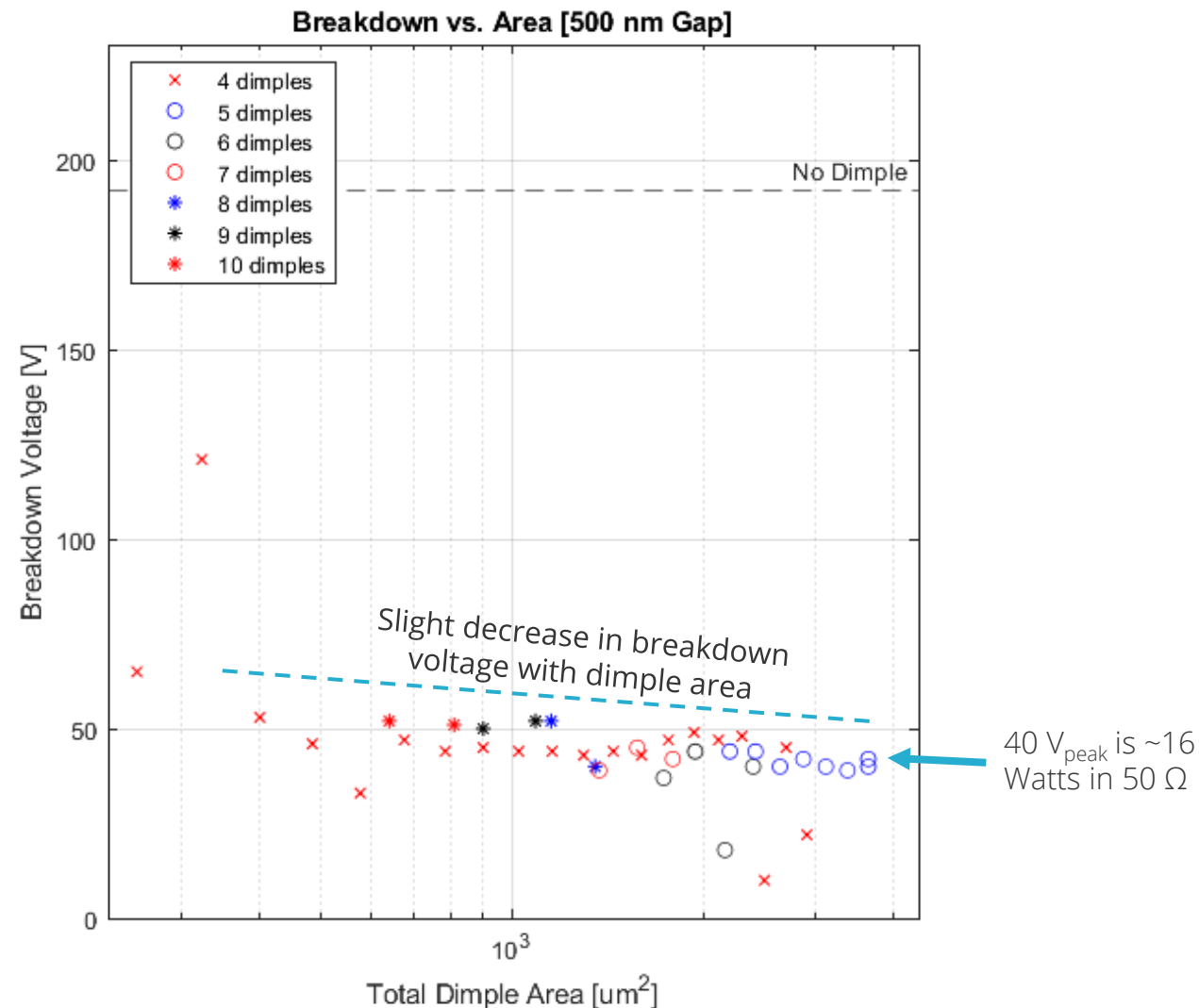
Field emission in vacuum – threshold fields of 15-30 MV/m



DC Screening Results – Vertical Devices



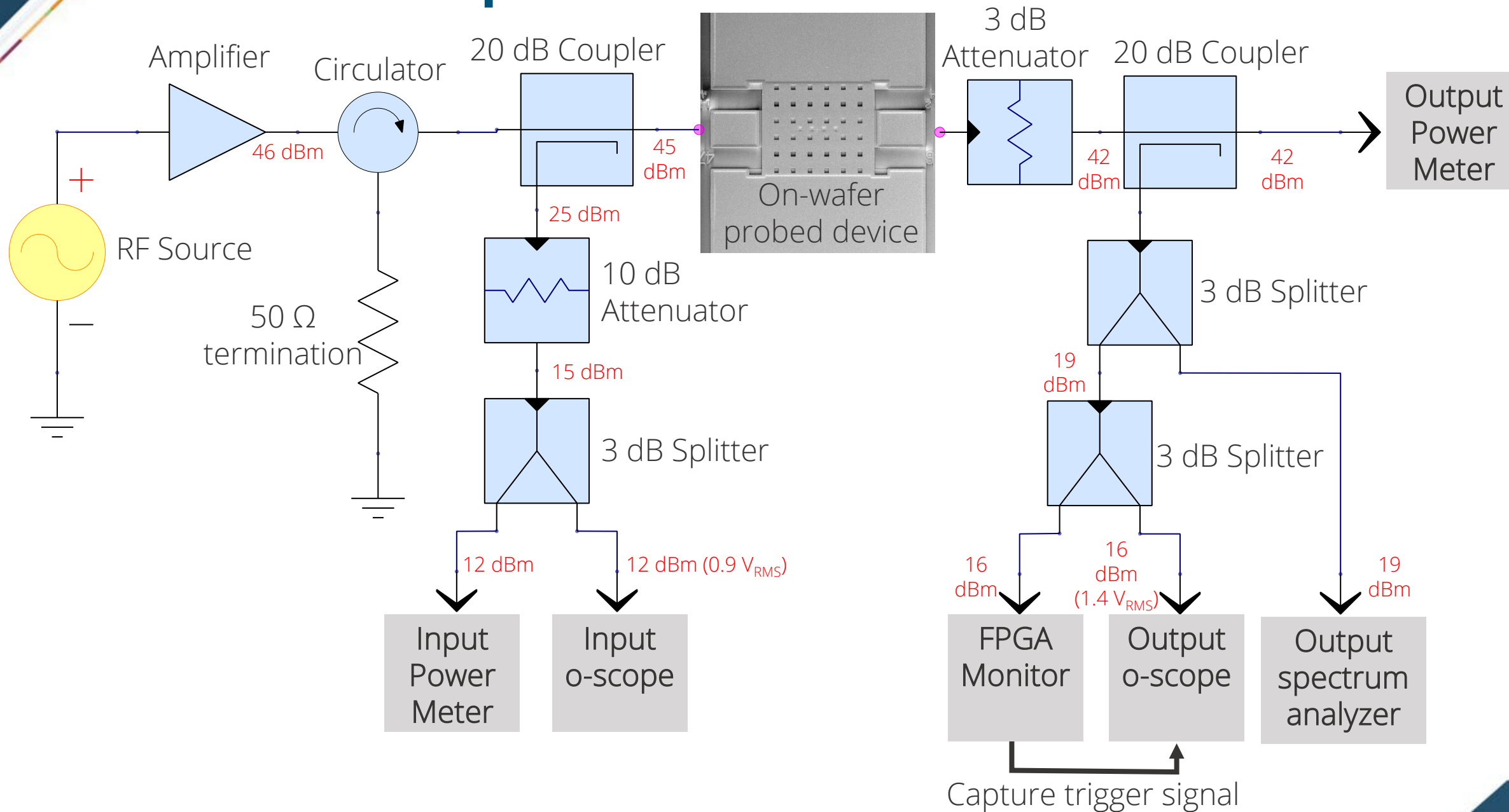
IV curves each correspond to
~60 separate devices on die



Onset of breakdown
vs. dimple area



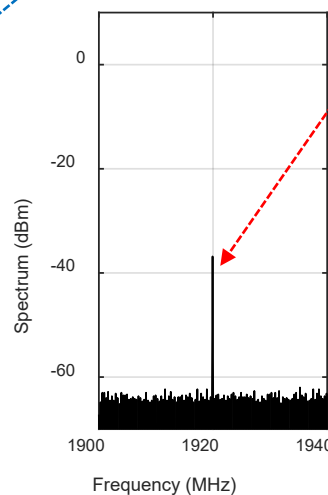
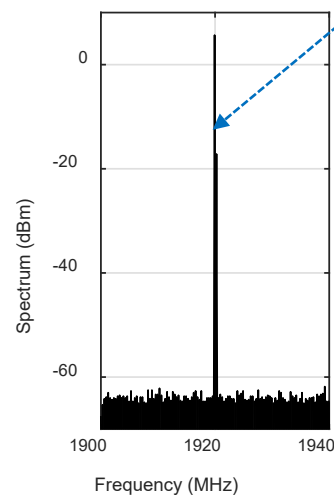
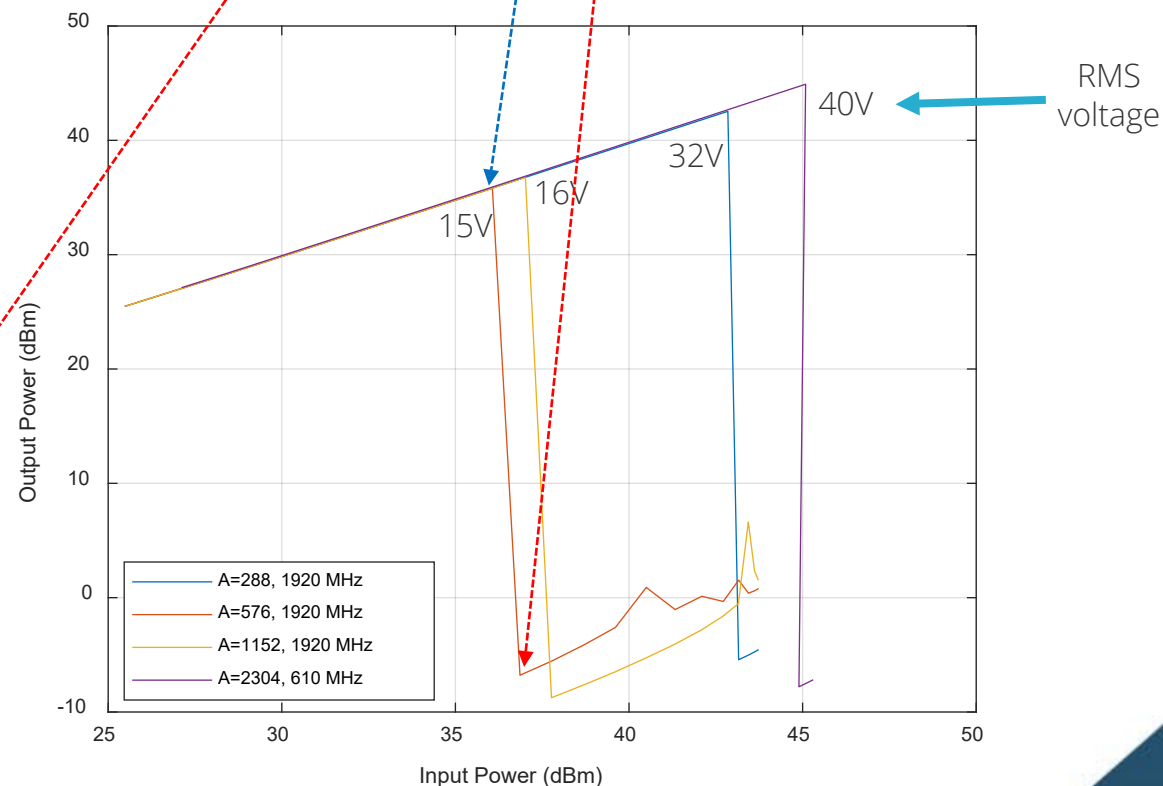
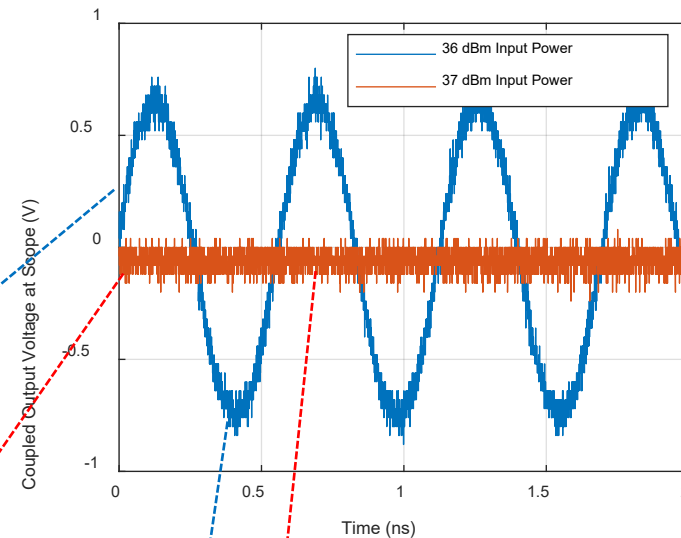
RF Test Setup



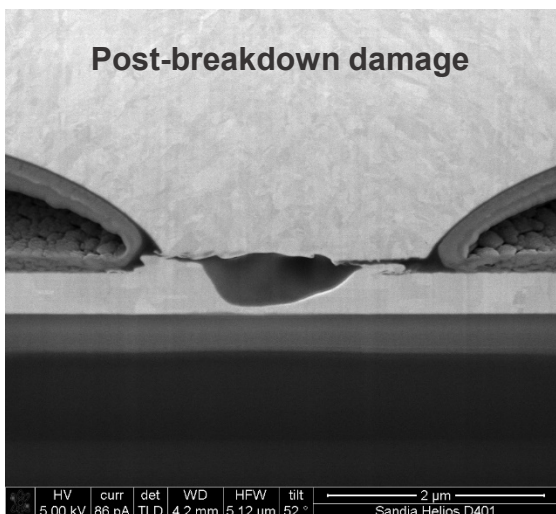


Initial RF Test Results

- Initial test results at small range of areas and frequencies.
- Preliminary observations based on limited dataset:
 - Breakdown decreases with increasing area
 - Breakdown decreases with increasing frequency
- Breakdown is permanent in all cases: arcing vs. alpha regime (P & T)
- Plan to repeat experiment with more frequencies and areas.



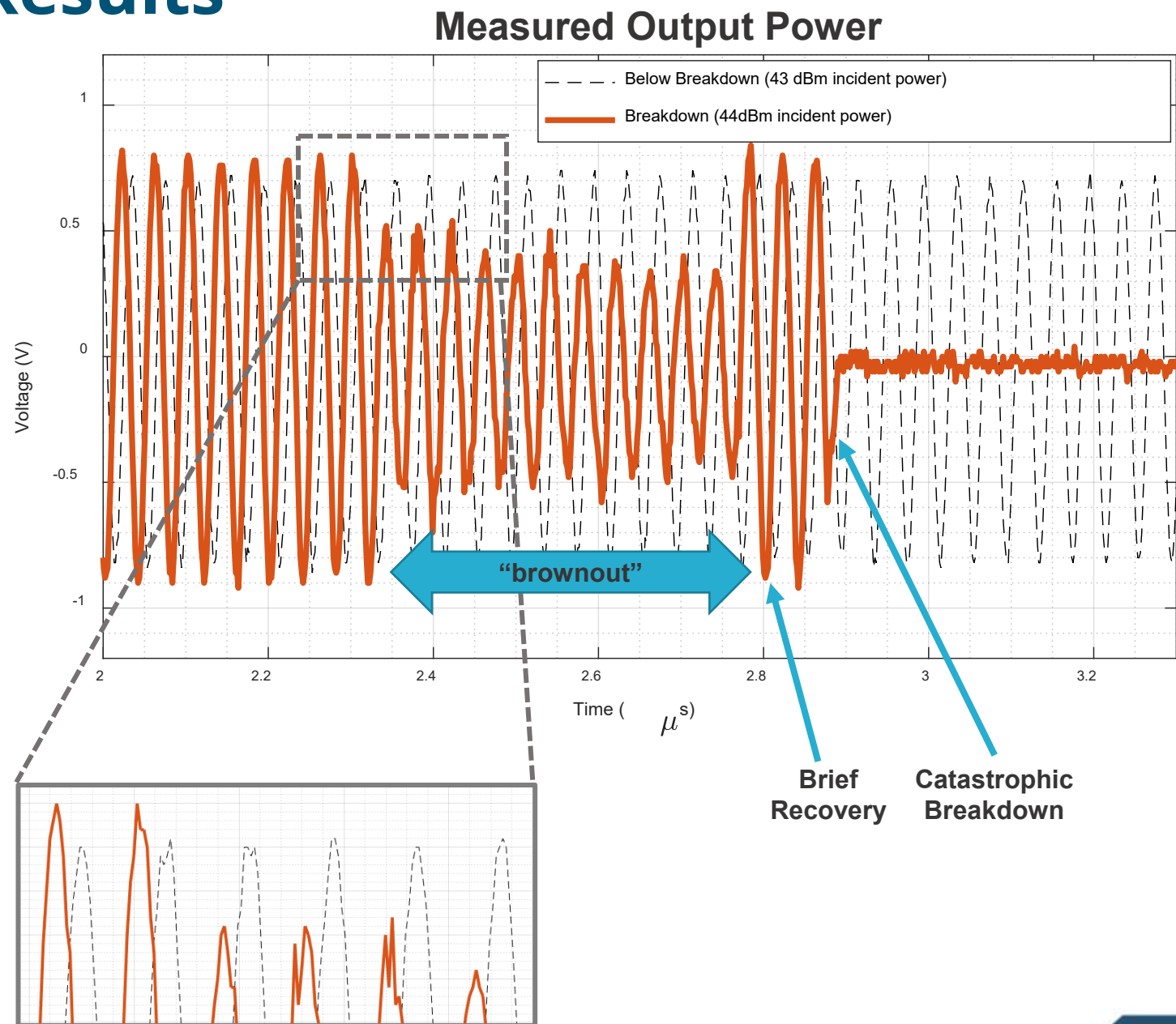
Post-breakdown damage





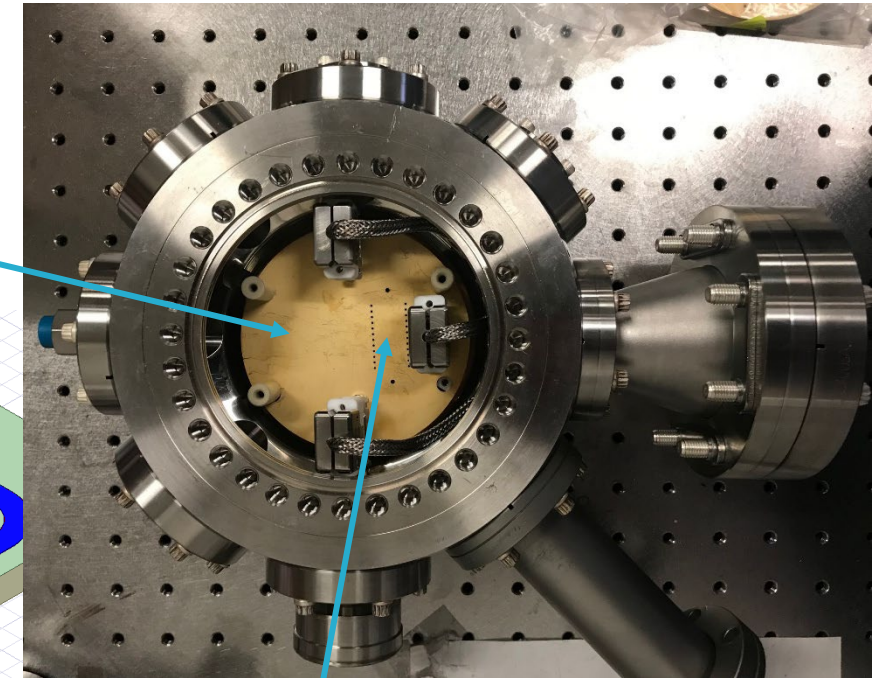
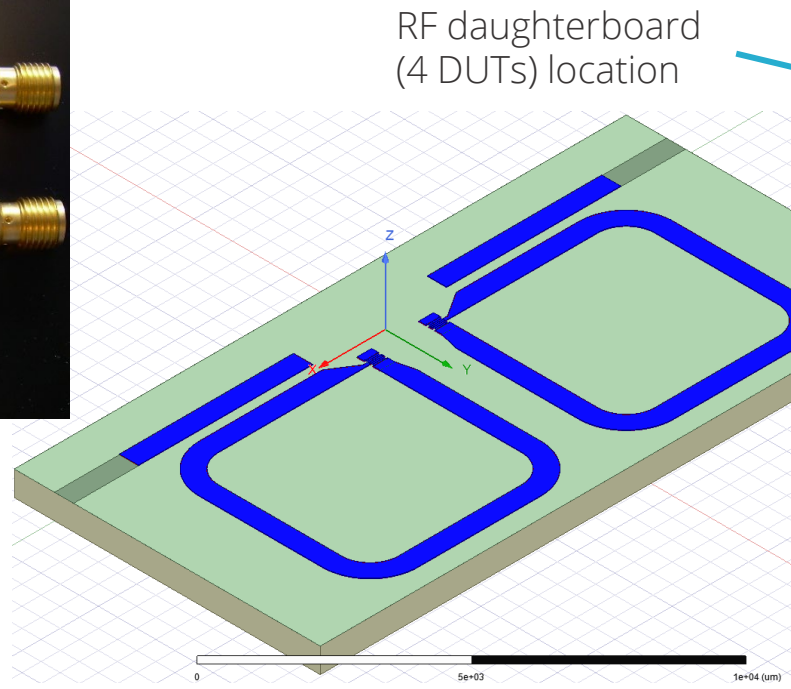
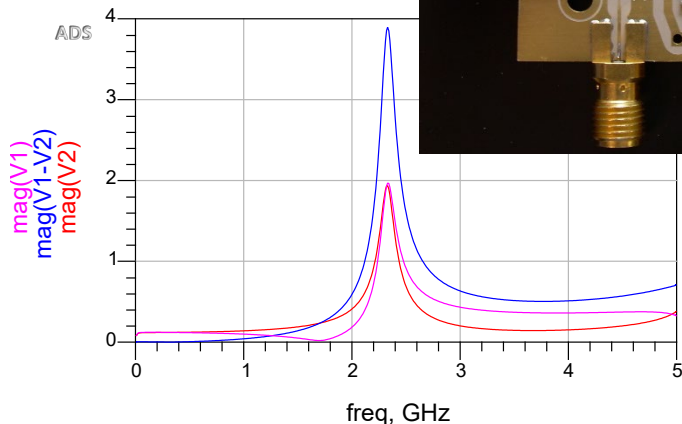
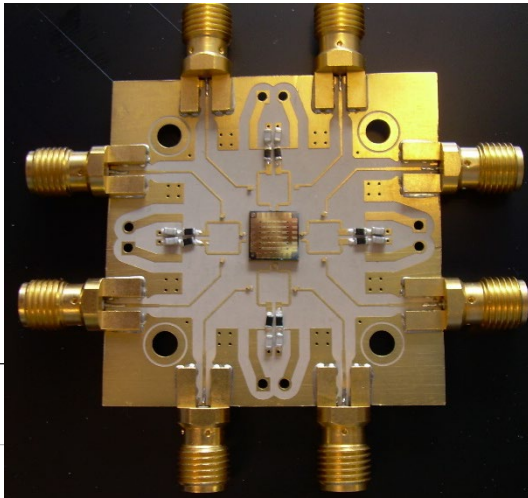
Time Domain RF Results

- Use real-time data capture to determine temporal nature of RF breakdown
- FPGA compares device output to a mask, and triggers scope upon deviations
- Scope captures portion of the waveform before and after breakdown
- Observations:
 - Some “brownouts” where power drops by a few dB for a few cycles (~200 nanoseconds)
 - Catastrophic breakdown happens quickly, within a cycle
 - Timescales are consistent with arcing
 - Possibly some additional “arcing” at the waveform peaks when approaching breakdown
 - More work to be done here



Next Steps

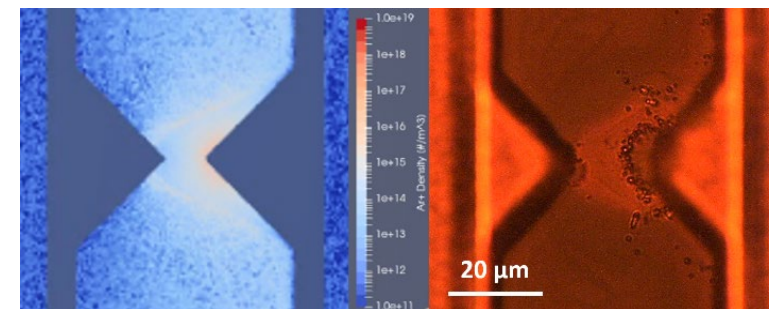
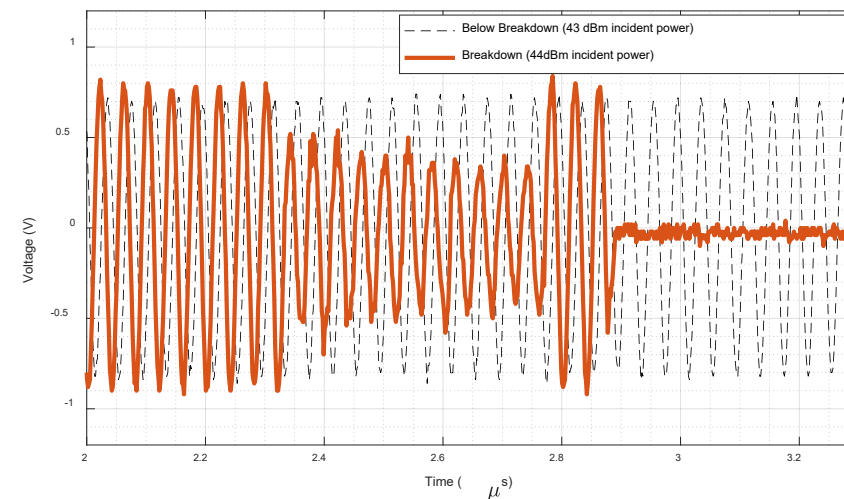
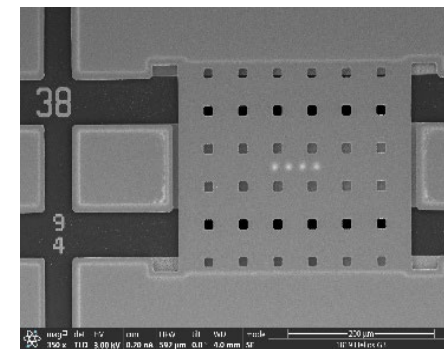
- Additional measurements at varied frequencies and dimple areas in air.
- Correlate modeled and measured results.
- Measurements in vacuum and other environments (move from arcing to alpha regime)
- Integration into resonators, filters, antennas, and other devices.
- Application of results into other technologies and areas.



24-pin DIP package
(20 DUTs) goes here



- [illegible]





Acknowledgements

Past & Present Funding Sources



LDRD

Laboratory Directed Research and Development



U.S. DEPARTMENT OF
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